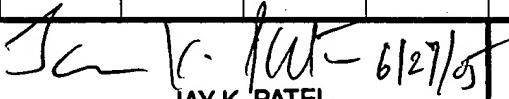
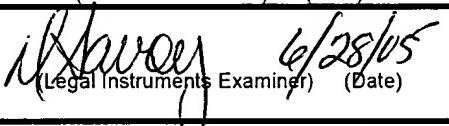


Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				09/934,693		AHN, KEUN HEE	
				Examiner		Art Unit	
				Jacob Meek		2637	

ORIGINAL				CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
375	326	375	233	350			
INTERNATIONAL CLASSIFICATION							
H	0	4	L	27/38			
H	0	4	B	1/10			
			/				
			/				
			/				
Jacob Meek 6/24/05 (Assistant Examiner) (Date)   JAY K. PATEL SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date)				Total Claims Allowed: 16 1 5			
 (Legal Instruments Examiner) (Date)				O.G. Print Claim(s)	O.G. Print Fig.		

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	1	31		61		91	
2	2	32		62		92	
3	3	33		63		93	
4	4	34		64		94	
5	5	35		65		95	
6	6	36		66		96	
7	7	37		67		97	
8	8	38		68		98	
9	9	39		69		99	
10	10	40		70		100	
11	11	41		71		101	
12	12	42		72		102	
13	13	43		73		103	
14	14	44		74		104	
15	15	45		75		105	
16	16	46		76		106	
17	17	47		77		107	
18	18	48		78		108	
19	19	49		79		109	
20		50		80		110	
21		51		81		111	
22		52		82		112	
23		53		83		113	
24		54		84		114	
25		55		85		115	
26		56		86		116	
27		57		87		117	
28		58		88		118	
29		59		89		119	
30		60		90		120	